

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1585	Feb-96	9452 B2	HYUNDAI	DL428089AAE	1.2μ OX/NI (2 Poly)	28 SOIC

STRESS/JOB NO.

READPOINT

(Sample Size/No. of Fails)

Preconditioning (P/C):
HTC Vapor Phase
P-16946

<u>Electrical</u>	<u>Cum %</u>
233/0	0.0%

Sonoscan
P-17284

<u>Post Vapor Phase</u>
2/0

Infant / High Voltage Life
125°C, 7.0 V.
P-17285, P-17734

<u>48 Hr</u>	<u>336 Hr</u>	<u>1K Hr</u>	<u>*Failure Rate</u>
231/0	77/1	76/0	67 Fits
	F1		

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-17735

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
38/0	38/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-17736

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
77/0	77/0	0.0%

Autoclave
121°C, 2 Atmos
P-17737

<u>96 Hr</u>	<u>Cum %</u>
38/1	2.6%
F2	

Failure Mode

F1: Functional
F2: Inleak Lo

Failure Analysis

In process, 960306
In process, 960307